

Notice of References Cited	Application/Control No. 10/695,225	Applicant(s)/Patent Under Reexamination TAKEUCHI ET AL.	
	Examiner Rebecca M. Stadler	Art Unit 1754	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,310,762	10-2001	Okamura et al.	361/502
*	B	US-3,770,625	11-1973		210/694
*	C	US-4,392,004	07-1983	D'Sidocky, Richard M.	585/820
*	D	US-4,725,422	02-1988	Miyabayashi et al.	423/445R
*	E	US-5,238,760	08-1993	Takahashi et al.	429/231.8
*	F	US-5,348,818	09-1994	Asami et al.	429/213
*	G	US-5,426,006	06-1995	Delnick et al.	429/221
*	H	US-6,316,144	11-2001	Xue et al.	429/231.4
*	I	US-6,738,252	05-2004	Okamura et al.	361/502
*	J	US-5,338,462	08-1994	Abe et al.	210/757
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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